

**EXPEDITED PROCEDURE – EXAMINING GROUP 2857**

**S/N 09/834,751**

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant:	Sergey A. Velichko et al.	Examiner:	Manuel L. Barbee
Serial No.:	09/834,751	Group Art Unit:	2857
Filed:	April 13, 2001	Docket No.:	303.750US1
Title:	CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING		

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**AMENDMENT & RESPONSE UNDER 37 C.F.R. 1.116**

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

In response to the Final Office Action mailed October 27, 2006, please amend the application as follows: